



512Mb DDR SDRAM Specification

A4S12D30FTP A4S12D40FTP



Zentel Electronics Corp.

Revision 1.2 May, 2011

512M Double Data Rate Synchronous DRAM

DESCRIPTION

A4S12D40FTP is a 4-bank x 8,388,608-word x 16-bit, A4S12D30FTP is a 4-bank x 16777216-word x 8-bit, double data rate synchronous DRAM, with SSTL_2 interface. All control and address signals are referenced to the rising edge of CLK. Input data is registered on both edges of data strobe, and output data and data strobe are referenced on both edges of CLK. The 512Mb DDR SDRAM achieves very high speed data rate up to 200MHz, and are suitable for main memory in computer systems.

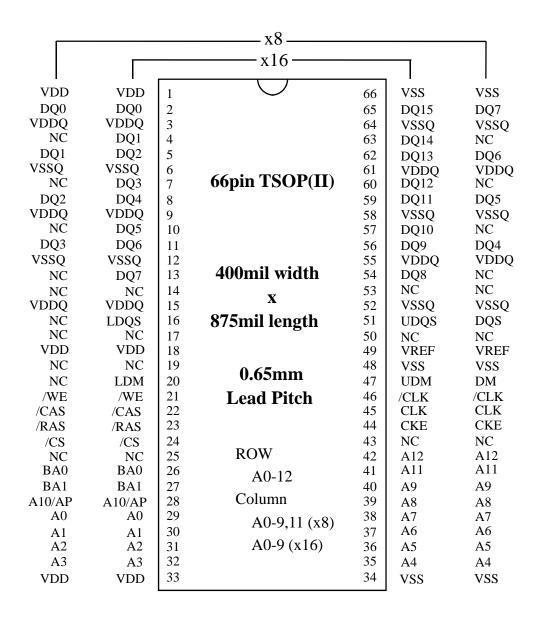
FEATURES

- $-Vdd=Vddq=2.5V\pm0.2V(G6 Grade)$
- $-Vdd=Vddq=2.6V\pm0.1V(G5 Grade)$
- Double data rate architecture; two data transfers per clock cycle
- Bidirectional, data strobe (DQS) is transmitted/received with data
- Differential clock inputs (CLK and /CLK)
- DLL aligns DQ and DQS transitions with CLK transitions edges of DQS
- Commands entered on each positive CLK edge;
- data and data mask referenced to both edges of DQS
- 4 bank operation controlled by BA0, BA1 (Bank Address)
- /CAS latency- 2.5/3.0 (programmable)
- Burst length- 2/4/8 (programmable)
- Burst type- sequential / interleave (programmable)
- Auto precharge / All bank precharge controlled by A10
- 8192 refresh cycles /64ms (4 banks concurrent refresh)
- Auto refresh and Self refresh
- Row address A0-12 / Column address A0-9,11(x8)/ A0-9(x16)
- SSTL 2 Interface
- 400-mil, 66-pin Thin Small Outline Package (TSOP II)

Zentel Electronics Corporation reserve the right to change products or specification without notice.



PIN CONFIGURATION(TOP VIEW)



CLK, /CLK : Master Clock A0-12 : Address Input
CKE : Clock Enable BA0,1 : Bank Address Input
/CS : Chip Select Vdd : Power Supply

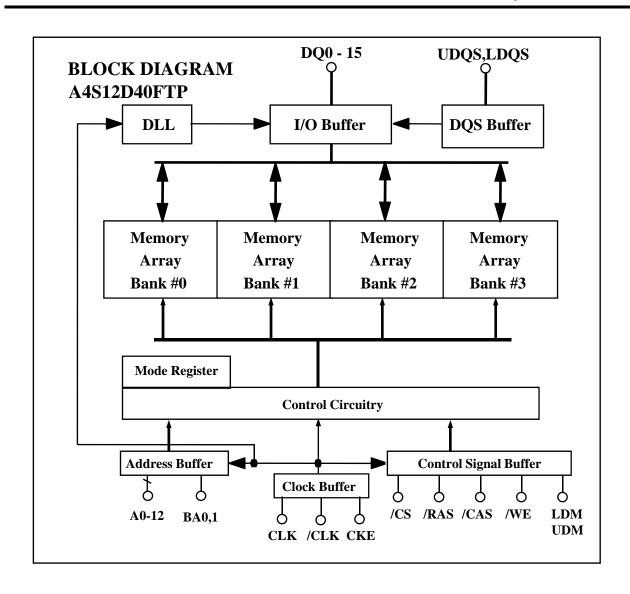
/RAS : Row Address Strobe VddQ : Power Supply for Output

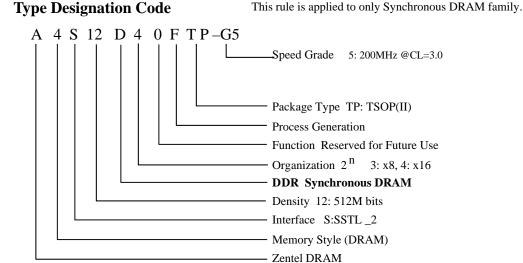
/CAS : Column Address Strobe Vss : Ground

/WE : Write Enable VssQ : Ground for Output DQ0-7 : Data I/O (x8) Vref : Reference Voltage

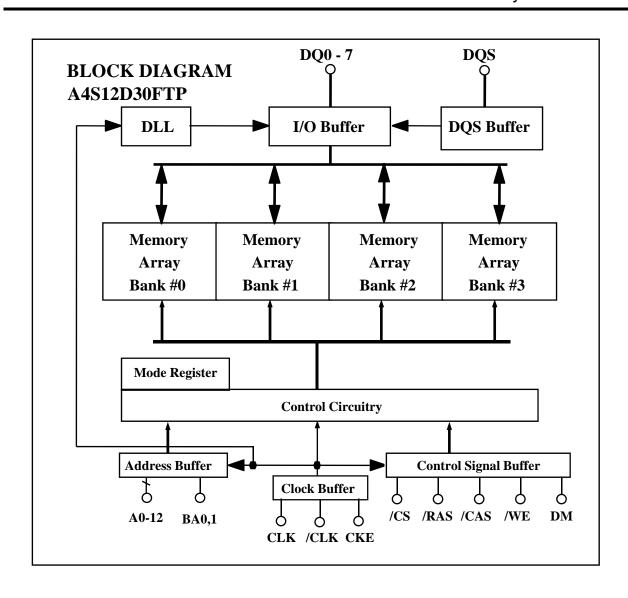
DQ0-15 : Data I/O (x16)
DQS : Data Strobe (x8)
UDQS, LDQS : Data Strobe (x16)
DM : Write Mask (x8)
UDM, LDM : Write Mask (x16)

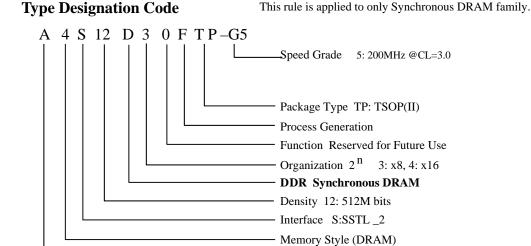












Zentel DRAM



512M Double Data Rate Synchronous DRAM

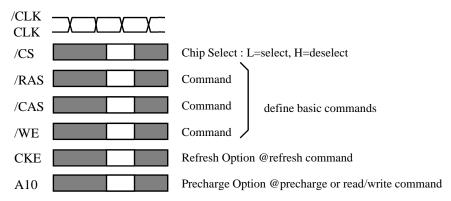
PIN FUNCTION

SYMBOL	ТҮРЕ	DESCRIPTION
CLK, /CLK	Input	Clock: CLK and /CLK are differential clock inputs. All address and control input signals are sampled on the crossing of the positive edge of CLK and negative edge of /CLK. Output (read) data is referenced to the crossings of CLK and /CLK (both directions of crossing).
CKE	Input	Clock Enable: CKE controls internal clock. When CKE is low, internal clock for the following cycle is ceased. CKE is also used to select auto / self refresh. After self refresh mode is started, CKE becomes asynchronous input. Self refresh is maintained as long as CKE is low.
/CS	Input	Chip Select: When /CS is high, any command means No Operation.
/RAS, /CAS, /WE	Input	Combination of /RAS, /CAS, /WE defines basic commands.
A0-12	Input	A0-12 specify the Row / Column Address in conjunction with BA0,1. The Row Address is specified by A0-12. The Column Address is specified by A0-9,11(x8) and A0-9(x16). A10 is also used to indicate precharge option. When A10 is high at a read / write command, an auto precharge is performed. When A10 is high at a precharge command, all banks are precharged.
BA0,1	Input	Bank Address: BA0,1 specifies one of four banks to which a command is applied. BA0,1 must be set with ACT, PRE, READ, WRITE commands.
DQ0-7 (x8), DQ0-15 (x16),	Input / Output	Data Input/Output: Data bus
DQS (x8) UDQS, LDQS (x16)	Input / Output	Data Strobe: Output with read data, input with write data. Edge-aligned with read data, centered in write data. Used to capture write data. For the x16, LDQS corresponds to the data on DQ0-DQ7; UDQS correspond to the data on DQ8-DQ15
DM (x8) UDM, LDM (x16)	Input	Input Data Mask: DM is an input mask signal for write data. Input data is masked when DM is sampled HIGH along with that input data during a WRITE access. DM is sampled on both edges of DQS. Although DM pins are input only, the DM loading matches the DQ and DQS loading. For the x16, LDM corresponds to the data on DQ0-DQ7; UDM corresponds to the data on DQ8-DQ15.
Vdd, Vss	Power Supply	Power Supply for the memory array and peripheral circuitry.
VddQ, VssQ	Power Supply	VddQ and VssQ are supplied to the Output Buffers only.
Vref	Input	SSTL_2 reference voltage.

512M Double Data Rate Synchronous DRAM

BASIC FUNCTIONS

The 512Mb DDR SDRAM provides basic functions, bank (row) activate, burst read / write, bank (row) precharge, and auto / self refresh. Each command is defined by control signals of /RAS, /CAS and /WE at CLK rising edge. In addition to 3 signals, /CS, CKE and A10 are used as chip select, refresh option, and precharge option, respectively. To know the detailed definition of commands, please see the command truth table.



Activate (ACT) [/RAS =L, /CAS =/WE =H]

ACT command activates a row in an idle bank indicated by BA.

Read (READ) [/RAS =H, /CAS =L, /WE =H]

READ command starts burst read from the active bank indicated by BA. First output data appears after /CAS latency. When A10 =H at this command, the bank is deactivated after the burst read (autoprecharge, **READA**)

Write (WRITE) [/RAS =H, /CAS =/WE =L]

WRITE command starts burst write to the active bank indicated by BA. Total data length to be written is set by burst length. When A10 =H at this command, the bank is deactivated after the burst write (auto-precharge, WRITEA)

Precharge (PRE) [/RAS = L, /CAS = H, /WE = L]

PRE command deactivates the active bank indicated by BA. This command also terminates burst read /write operation. When A10 =H at this command, all banks are deactivated (precharge all, **PREA**).

Auto-Refresh (REFA) [/RAS = /CAS = L, /WE = CKE = H]

REFA command starts auto-refresh cycle. Refresh address including bank address are generated internally. After this command, the banks are precharged automatically.

512M Double Data Rate Synchronous DRAM

COMMAND TRUTH TABLE

	l									I	
COMMAND	MNEMONIC	CKE n-1	CKE n	/CS	/RAS	/CAS	/WE	BA0,1	A10 /AP	A0-9, 11-12	note
Deselect	DESEL	Н	X	Н	X	X	X	X	X	X	
No Operation	NOP	Н	X	L	Н	Н	Н	X	X	X	
Row Address Entry & Bank Activate	ACT	Н	Н	L	L	Н	Н	V	V	V	
Single Bank Precharge	PRE	Н	Н	L	L	Н	L	V	L	X	
Precharge All Banks	PREA	Н	Н	L	L	Н	L	X	Н	X	
Column Address Entry & Write	WRITE	Н	Н	L	Н	L	L	V	L	V	
Column Address Entry & Write with Auto-Precharge	WRITEA	Н	Н	L	Н	L	L	V	Н	V	
Column Address Entry & Read	READ	Н	Н	L	Н	L	Н	V	L	V	
Column Address Entry & Read with Auto-Precharge	READA	Н	Н	L	Н	L	Н	V	Н	V	
Auto-Refresh	REFA	Н	Н	L	L	L	Н	X	X	X	
Self-Refresh Entry	REFS	Н	L	L	L	L	Н	X	X	X	
	DEEGN	L	Н	Н	X	X	X	X	X	X	
Self-Refresh Exit	REFSX	L	Н	L	Н	Н	Н	X	X	X	
Burst Terminate	TERM	Н	Н	L	Н	Н	L	X	X	X	1
Mode Register Set	MRS	Н	Н	L	L	L	L	L	L	V	2

H=High Level, L=Low Level, V=Valid, X=Don't Care, n=CLK cycle number

NOTE:

- 1. Applies only to read bursts with autoprecharge disabled; this command is undefined (and should not be used) for read bursts with autoprecharge enabled, and for write bursts.
- 2. BA0-BA1 select either the Base or the Extended Mode Register (BA0 = 0, BA1 = 0 selects Mode Register;BA0=1, BA1 = 0 selects Extended Mode Register; other combinations of BA0-BA1 are reserved; A0-A12 provide the op-code to be written to the selected Mode Register.



512M Double Data Rate Synchronous DRAM

FUNCTION TRUTH TABLE

Current State	/CS	/RAS	/CAS	/WE	Address	Command	Action	Notes
IDLE	Н	X	X	X	X	DESEL	NOP	
	L	Н	Н	Н	X	NOP	NOP	
	L	Н	Н	L	BA	TERM	ILLEGAL	2
	L	Н	L	X	BA, CA, A10	READ / WRITE	ILLEGAL	2
	L	L	Н	Н	BA, RA	ACT	Bank Active, Latch RA	
	L	L	Н	L	BA, A10	PRE / PREA	NOP	4
	L	L	L	Н	X	REFA	Auto-Refresh	5
	L	L	L	L	Op-Code, Mode- Add	MRS	Mode Register Set	5
ROW ACTIVE	Н	X	X	X	X	DESEL	NOP	
	L	Н	Н	Н	X	NOP	NOP	
	L	Н	Н	L	BA	TERM	NOP	
	L	Н	L	Н	BA, CA, A10	READ / READA	Begin Read, Latch CA, Determine	
	L	11	ь	11	DA, CA, ATO	KLAD / KLADA	Auto-Precharge	
	L	Н	L	L	BA, CA, A10	IWRITH / WRITHA I	Begin Write, Latch CA, Determine	
	т .	· ·	77			Auto-Precharge		1 2
	L	L	Н		BA, RA	ACT	Bank Active / ILLEGAL	2
	L	L	Н		BA, A10	PRE / PREA	Precharge / Precharge All	
	L	L	L	Н	X	REFA	ILLEGAL	
	L	L	L	L	Op-Code, Mode- Add	MRS	ILLEGAL	
READ(Auto-	Н	X	X		X	DESEL	NOP (Continue Burst to END)	
Precharge	L	Н	Н	Н	X	NOP	NOP (Continue Burst to END)	
Disabled)	L	Н	Н	L	BA	TERM	Terminate Burst	
	L	Н	L	Н	BA, CA, A10	READ / READA	Terminate Burst, Latch CA, Begin New Read, Determine Auto- Precharge	3
	L	Н	L	L	BA, CA, A10	WRITE / WRITEA	ILLEGAL	
	L	L	Н	Н	BA, RA	ACT	Bank Active / ILLEGAL	2
	L	L	Н	L	BA, A10	PRE / PREA	Terminate Burst, Precharge	
	L	L	L	Н	X	REFA	ILLEGAL	
	L	L	L	L	Op-Code, Mode- Add	MRS	ILLEGAL	



512M Double Data Rate Synchronous DRAM

FUNCTION TRUTH TABLE (continued)

Current State	/CS	/RAS	/CAS	/WE	Address	Command	Action	Notes
WRITE(Auto-	Н	X	X	X	X	DESEL	NOP (Continue Burst to END)	
Precharge	L	Н	Н	Н	X	NOP	NOP (Continue Burst to END)	
Disabled)	L	Н	Н	L	BA	TERM	ILLEGAL	
	L	Н	L	Н	BA, CA, A10	READ / READA	Terminate Burst, Latch CA, Begin Read, Determine Auto-Precharge	3
	L	Н	L	L	BA, CA, A10	WRITE / WRITEA	Terminate Burst, Latch CA, Begin Write, Determine Auto-Precharge	3
	L	L	Н	Н	BA, RA	ACT	Bank Active / ILLEGAL	2
	L	L	Н	L	BA, A10	PRE / PREA	Terminate Burst, Precharge	
	L	L	L	Н	X	REFA	ILLEGAL	
	L	L	L	L	Op-Code, Mode- Add	MRS	ILLEGAL	
DE 1 D 11	Н	X	X	X	X	DESEL	NOP (Continue Burst to END)	
READ with	L	Н	Н	Н	X	NOP	NOP (Continue Burst to END)	
Auto-Precharge	L	Н	Н	L	BA	TERM	ILLEGAL	
	L	Н	L	Н	BA, CA, A10	READ / READA	ILLEGAL	6
	L	Н	L	L	BA, CA, A10	WRITE / WRITEA	ILLEGAL	6
	L	L	Н	Н	BA, RA	ACT	Bank Active / ILLEGAL	2,6
	L	L	Н	L	BA, A10	PRE / PREA	Precharge / ILLEGAL	2,6
	L	L	L	Н	X	REFA	ILLEGAL	
	L	L	L	L	Op-Code, Mode- Add	MRS	ILLEGAL	
MIDIOE 14	Н	X	X	X	X	DESEL	NOP (Continue Burst to END)	
WRITE with	L	Н	Н	Н	X	NOP	NOP (Continue Burst to END)	
Auto-Precharge	L	Н	Н	L	BA	TERM	ILLEGAL	
	L	Н	L	Н	BA, CA, A10	READ / READA	ILLEGAL	6
	L	Н	L	L	BA, CA, A10	WRITE / WRITEA	ILLEGAL	6
	L	L	Н	Н	BA, RA	ACT	Bank Active / ILLEGAL	2,6
	L	L	Н	L	BA, A10	PRE / PREA	Precharge / ILLEGAL	2,6
	L	L	L	Н	X	REFA	ILLEGAL	
	L	L	L	L	Op-Code, Mode- Add	MRS	ILLEGAL	



512M Double Data Rate Synchronous DRAM

FUNCTION TRUTH TABLE (continued)

Current State	/CS	/RAS	/CAS	/WE	Address	Command	Action	Notes
PRE-	Н	X	X	X	X	DESEL	NOP (Idle after tRP)	
CHARGING	L	Н	Н	Н	X	NOP	NOP (Idle after tRP)	
	L	Н	Н	L	BA	TERM	ILLEGAL	2
	L	Н	L	X	BA, CA, A10	READ / WRITE	ILLEGAL	2
	L	L	Н	Н	BA, RA	ACT	ILLEGAL	2
	L	L	Н	L	BA, A10	PRE / PREA	NOP (Idle after tRP)	4
	L	L	L	Н	X	REFA	ILLEGAL	
	L	L	L	L	Op-Code, Mode- Add	MRS	ILLEGAL	
DOW	Н	X	X	X	X	DESEL	NOP (Row Active after tRCD)	
ROW ACTIVATING	L	Н	Н	Н	X	NOP	NOP (Row Active after tRCD)	
ACTIVATING	L	Н	Н	L	BA	TERM	ILLEGAL	2
	L	Н	L	X	BA, CA, A10	READ / WRITE	ILLEGAL	2
	L	L	Н	Н	BA, RA	ACT	ILLEGAL	2
	L	L	Н	L	BA, A10	PRE / PREA	ILLEGAL	2
	L	L	L	Н	X	REFA	ILLEGAL	
	L	L	L	L	Op-Code, Mode- Add	MRS	ILLEGAL	
WIDNE DE	Н	X	X	X	X	DESEL	NOP	
WRITE RE- COVERING	L	Н	Н	Н	X	NOP	NOP	
COVERING	L	Н	Н	L	BA	TERM	ILLEGAL	2
	L	Н	L	X	BA, CA, A10	READ / WRITE	ILLEGAL	2
	L	L	Н	Н	BA, RA	ACT	ILLEGAL	2
	L	L	Н	L	BA, A10	PRE / PREA	ILLEGAL	2
	L	L	L	Н	X	REFA	ILLEGAL	
		Op-Code, Mode- Add	MRS	ILLEGAL				



512M Double Data Rate Synchronous DRAM

FUNCTION TRUTH TABLE (continued)

Current State	/CS	/RAS	/CAS	/WE	Address	Command	Action	Notes
REFRESHING	Н	X	X	X	X	DESEL	NOP (Idle after tRC)	
	L	Н	Н	Н	X	NOP	NOP (Idle after tRC)	
	L	Н	Н	L	BA	TERM	ILLEGAL	
	L	Н	L	X	BA, CA, A10	READ / WRITE	ILLEGAL	
	L	L	Н	Н	BA, RA	ACT	ILLEGAL	
	L	L	Н	L	BA, A10	PRE / PREA	ILLEGAL	
	L	L	L	Н	X	REFA	ILLEGAL	
	L	L	L	L	Op-Code, Mode- Add	MRS	ILLEGAL	
MODE	Н	X	X	X	X	DESEL	NOP (Row Active after tRSC)	
REGISTER	L	Н	Н	Н	X	NOP	NOP (Row Active after tRSC)	
SETTING	L	Н	Н	L	BA	TERM	ILLEGAL	
	L	Н	L	X	BA, CA, A10	READ / WRITE	ILLEGAL	
	L	L	Н	Н	BA, RA	ACT	ILLEGAL	
	L	L	Н	L	BA, A10	PRE / PREA	ILLEGAL	
	L	L	L	Н	X	REFA	ILLEGAL	
	L	L	L	L	Op-Code, Mode- Add	MRS	ILLEGAL	

ABBREVIATIONS:

H=High Level, L=Low Level, X=Don't Care

BA=Bank Address, RA=Row Address, CA=Column Address, NOP=No Operation

NOTES:

- 1. All entries assume that CKE was High during the preceding clock cycle and the current clock cycle.
- 2. ILLEGAL to bank in specified state; function may be legal in the bank indicated by BA, depending on the state of that bank.
- 3. Must satisfy bus contention, bus turn around, write recovery requirements.
- 4. NOP to bank precharging or in idle state. May precharge bank indicated by BA.
- 5. ILLEGAL if any bank is not idle.
- 6.The DDR SDRAM supports the concurrent auto-precharge feature, a read with auto-precharge enabled, or a write with auto-precharge enabled, may be followed by any column command to other banks, as long as that command does not interrupt the read or write data transfer, and all other related limitations apply. (E.g. Conflict between READ data and WRITE data must be avoided.)

The minimum delay from a read or write command with auto precharge enabled, to a command to a different bank, is summarized below.

	To command(different bank, non-	Minimum delay	
From command	interrupting command)	(Concurrent AP supported)	Units
Read w/AP	Read or Read w/AP	BL/2	tCK
	Write or Write w/AP	CL(rounded up)+(BL/2)	tCK
	Precharge or Activate	1	tCK
Write w/AP	Read or Read w/AP	1+(BL/2)+tWTR	tCK
	Write or Write w/AP	BL/2	tCK
	Prcharge or Activate	1	tCK

 $ILLEGAL = Device\ operation\ and/or\ data-integrity\ are\ not\ guaranteed.$

FUNCTION TRUTH TABLE for CKE

Current State	CKE n-1	CKE n	/CS	/RAS	/CAS	/WE	Address	Action	Notes
SELF-	Н	X	X	X	X	X	X	INVALID	1
REFRESHING	L	Н	Н	X	X	X	X	Exit Self-Refresh (Idle after tRC)	1
	L	Н	L	Н	Н	Н	Х	Exit Self-Refresh (Idle after tRC)	1
	L	Н	L	Н	Н	L	Х	ILLEGAL	1
	L	Н	L	Н	L	X	X	ILLEGAL	1
	L	Н	L	L	X	X	X	ILLEGAL	1
	L	L	X	X	X	X	X	NOP (Maintain Self-Refresh)	1
POWER	Н	X	X	X	X	X	X	INVALID	
DOWN	L	Н	X	X	X	X	X	Exit Power Down to Idle	
	L	L	X	X	X	X	X	NOP (Maintain Self-Refresh)	
ALL BANKS	Н	Н	X	X	X	X	X	Refer to Function Truth Table	2
IDLE	Н	L	L	L	L	Н	X	Enter Self-Refresh	2
	Н	L	Н	X	X	X	X	Enter Power Down	2
	Н	L	L	Н	Н	Н	X	Enter Power Down	2
	Н	L	L	Н	Н	L	X	ILLEGAL	2
	Н	L	L	Н	L	X	X	ILLEGAL	2
	Н	L	L	L	X	X	X	ILLEGAL	2
	L	X	X	X	X	X	X	Refer to Current State =Power Down	2
ANY STATE	Н	Н	X	X	X	X	X	Refer to Function Truth Table	
other than listed	Н	L	X	X	X	X	X	Begin CLK Suspend at Next Cycle	3
above	L	Н	X	X	X	X	X	Exit CLK Suspend at Next Cycle	3
	L	L	X	X	X	X	X	Maintain CLK Suspend	

ABBREVIATIONS:

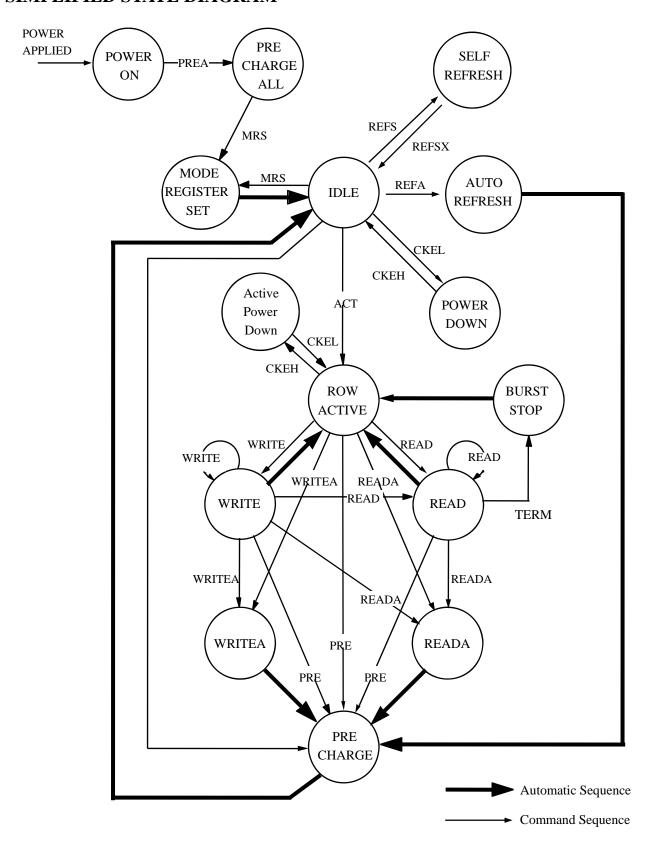
H=High Level, L=Low Level, X=Don't Care

NOTES:

- 1. CKE Low to High transition will re-enable CLK and other inputs asynchronously. A minimum setup time must be satisfied before any command other than EXIT.
- 2. Power-Down and Self-Refresh can be entered only from the All Banks Idle State.
- 3. Must be legal command.



SIMPLIFIED STATE DIAGRAM

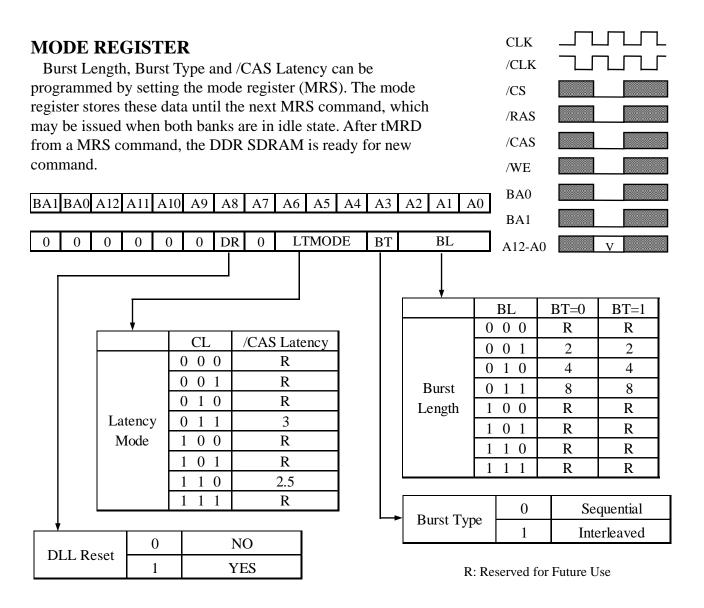


POWER ON SEQUENCE

Before starting normal operation, the following power on sequence is necessary to prevent a SDRAM from damaged or multifunctioning.

- 1. Apply VDD before or the same time as VDDQ
- 2. Apply VDDQ before or at the same time as VTT & Vref
- 3. Maintain stable condition for 200us after stable power and CLK, apply NOP or DSEL
- 4. Issue precharge command for all banks of the device
- 5. Issue EMRS to enable DLL.
- 6. Issue MRS to reset DLL and maintain 200 cycles of clock to lock the DLL.
- 7. Issue precharge command for all banks of the device
- 8. Issue 2 or more Auto Refresh commands
- 9. Issue MRS command to initialize device operation.

After these sequence, the DDR SDRAM is idle state and ready for normal operation.



512M Double Data Rate Synchronous DRAM

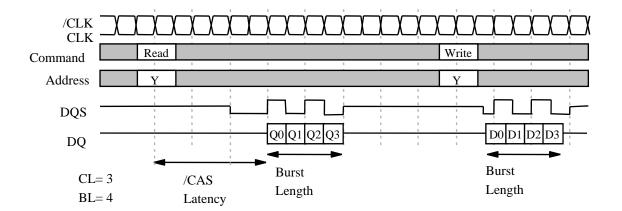
A12-A0

EXTENDED MODE REGISTER

DLL disable / enable mode can be programmed by setting the extended CLK mode register (EMRS). The extended mode register stores these data until the next EMRS command, which may be issued when all banks are /CLK in idle state. After tMRD from a EMRS command, the DDR SDRAM is /CS ready for new command. /RAS /CAS /WE BA1 BA0 A12 A11 A10 A9 A8 A7 A6 A5 A4 A3 A0 BA0 0 1 0 0 0 0 0 0 0 0 0 0 0 DS DD BA1







Initia	al Add	lress	BL		Column Addressing														
A2	A1	A0					Seque	ential					Interleaved						
0	0	0		0	1	2	3	4	5	6	7	0	1	2	3	4	5	6	7
0	0	1		1	2	3	4	5	6	7	0	1	0	3	2	5	4	7	6
0	1	0		2	3	4	5	6	7	0	1	2	3	0	1	6	7	4	5
0	1	1		3	4	5	6	7	0	1	2	3	2	1	0	7	6	5	4
1	0	0	8	4	5	6	7	0	1	2	3	4	5	6	7	0	1	2	3
1	0	1		5	6	7	0	1	2	3	4	5	4	7	6	1	0	3	2
1	1	0		6	7	0	1	2	3	4	5	6	7	4	5	2	3	0	1
1	1	1		7	0	1	2	3	4	5	6	7	6	5	4	3	2	1	0
-	0	0		0	1	2	3					0	1	2	3				
-	0	1	4	1	2	3	0					1	0	3	2				
-	1	0	4	2	3	0	1					2	3	0	1				
-	1	1		3	0	1	2					3	2	1	0				
-	1	0	2	0	1							0	1						
-	-	1	2	1	0							1	0						

A4S12D30FTP



OPERATIONAL DESCRIPTION

BANK ACTIVATE

The DDR SDRAM has four independent banks. Each bank is activated by the ACT command with the bank addresses (BA0,1). A row is indicated by the row address A12-0. The minimum activation interval between one bank and the other bank is tRRD.

PRECHARGE

DO -

The PRE command deactivates the bank indicated by BA0,1. When multiple banks are active, the precharge all command (PREA,PRE+A10=H) is available to deactivate them at the same time. After tRP from the precharge, an ACT command to the same bank can be issued.

2 ACT command / tRC min (same bank) tRCmin ACT READ ACT PRE ACT Command tRRD tRP tRAS A0-9,11,12 Xa Xb Y tRCD BL/2 A10 Xa Xb 0 Xb BA0,1 00 **DQS**

Bank Activation and Precharge All (BL=8, CL=3)

A precharge command can be issued at BL/2 from a read command without data loss.

Qa3

Precharge all

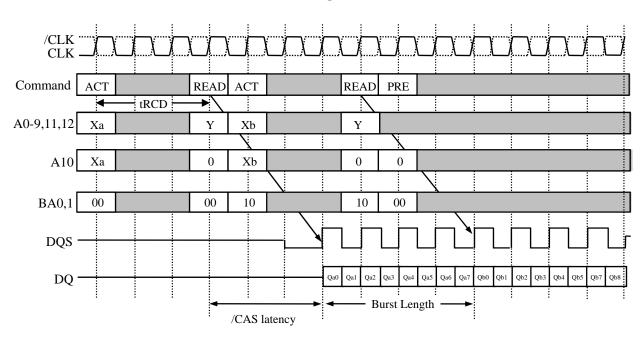
Qa5



READ

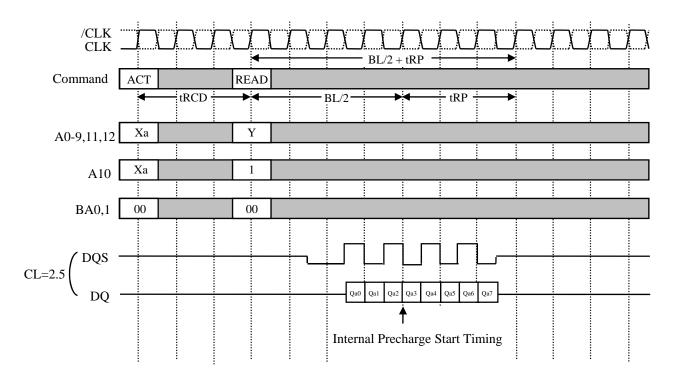
After tRCD from the bank activation, a READ command can be issued. 1st Output data is available after the /CAS Latency from the READ, followed by (BL-1) consecutive data when the Burst Length is BL. The start address is specified by A12,A11,A9-A0(x8)/A9-A0(x16), and the address sequence of burst data is defined by the Burst Type. A READ command may be applied to any active bank, so the row precharge time (tRP) can be hidden behind continuous output data by interleaving the multiple banks. When A10 is high at a READ command, the auto-precharge (READA) is performed. Any command(READ,WRITE,PRE,ACT) to the same bank is inhibited till the internal precharge is complete. The internal precharge starts at BL/2 after READA. The next ACT command can be issued after (BL/2+tRP) from the previous READA.

Multi Bank Interleaving READ (BL=8, CL=3)





READ with Auto-Precharge (BL=8, CL=2.5)

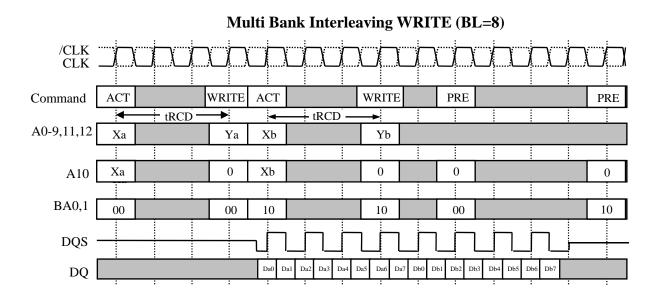


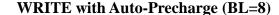
Read with auto-precharge command does not limit row commands execution for other bank . Refer to 'FUNCTION TRUTH TABLE' and related note (Notes 6)

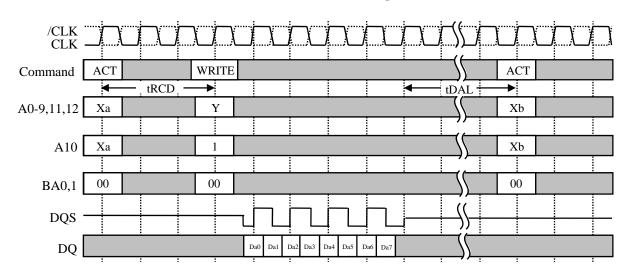


WRITE

After tRCD from the bank activation, a WRITE command can be issued. 1st input data is set from the WRITE command with data strobe input, following (BL-1) data are written into RAM, when the Burst Length is BL. The start address is specified by A12,A11,A9-A0(x8)/A9-A0(x16), and the address sequence of burst data is defined by the Burst Type. A WRITE command may be applied to any active bank, so the row precharge time (tRP) can be hidden behind continuous input data by interleaving the multiple banks. From the last data to the PRE command, the write recovery time (tWRP) is required. When A10 is high at a WRITE command, the auto-precharge(WRITEA) is performed. Any command(READ,WRITE,PRE,ACT) to the same bank is inhibited till the internal precharge is complete. The next ACT command can be issued after tDAL from the last input data cycle.





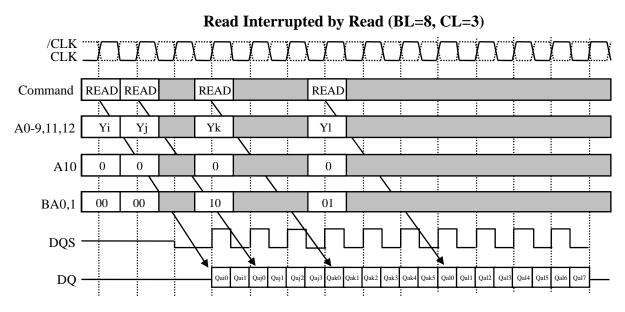




BURST INTERRUPTION

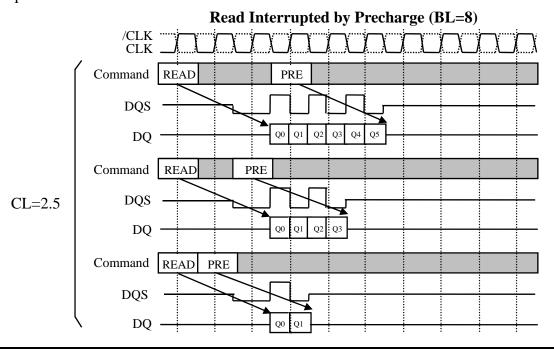
[Read Interrupted by Read]

Burst read operation can be interrupted by new read of any bank. Random column access is allowed. READ to READ interval is minimum 1CLK.



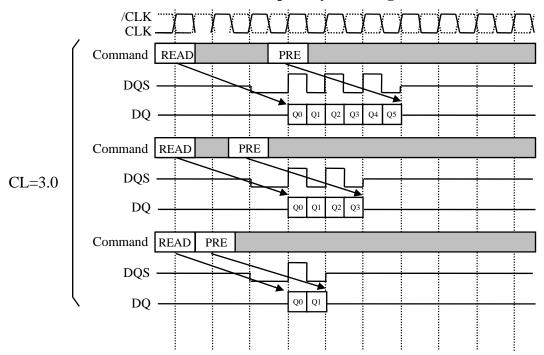
[Read Interrupted by precharge]

Burst read operation can be interrupted by precharge of the same bank. READ to PRE interval is minimum 1 CLK. A PRE command to output disable latency is equivalent to the /CAS Latency. As a result, READ to PRE interval determines valid data length to be output. The figure below shows examples of BL=8.





Read Interrupted by Precharge (BL=8)



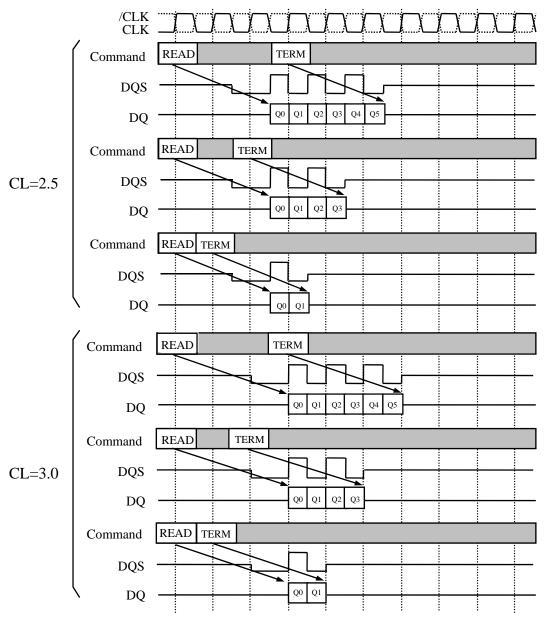




[Read Interrupted by Burst Stop]

Burst read operation can be interrupted by a burst stop command(TERM). READ to TERM interval is minimum 1 CLK. A TERM command to output disable latency is equivalent to the /CAS Latency. As a result, READ to TERM interval determines valid data length to be output. The figure below shows examples of BL=8.

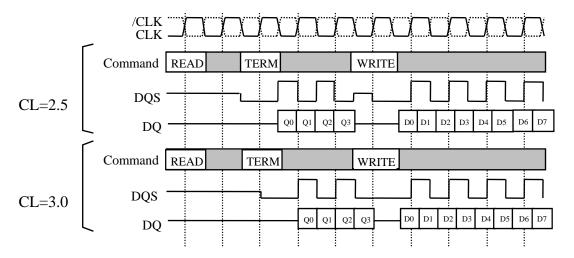
Read Interrupted by TERM (BL=8)





[Read Interrupted by Write with TERM]

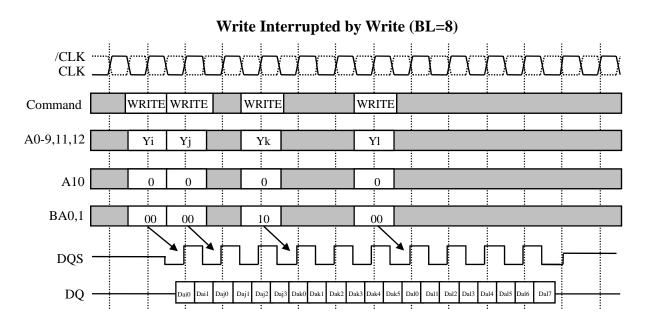
Read Interrupted by TERM (BL=8)





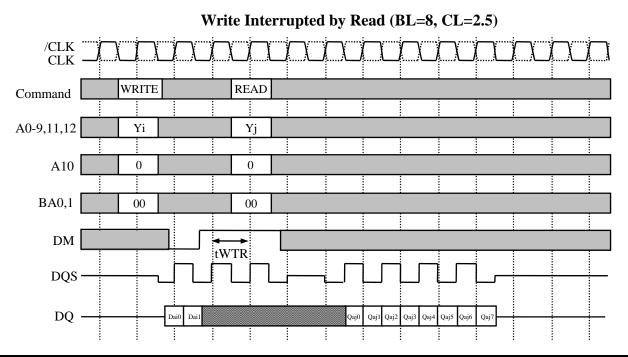
[Write interrupted by Write]

Burst write operation can be interrupted by write of any bank. Random column access is allowed. WRITE to WRITE interval is minimum 1 CLK.



[Write interrupted by Read]

Burst write operation can be interrupted by read of the same or the other bank. Random column access is allowed. Internal WRITE to READ command interval(tWTR) is minimum 1 CLK. The input data on DQ at the interrupting READ cycle is "don't care". tWTR is referenced from the first positive edge after the last data input.



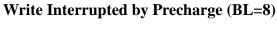
Revision 1.2 Page 25 / 37 May, 2011

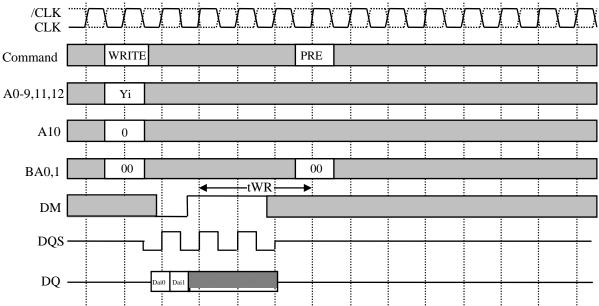
A4S12D30FTP



[Write interrupted by Precharge]

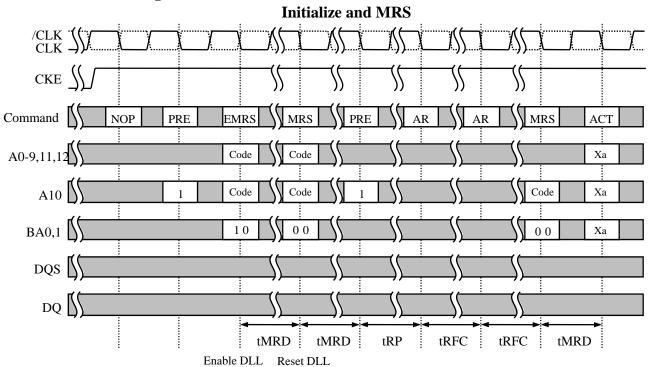
Burst write operation can be interrupted by precharge of the same or all bank. Random column access is allowed. tWR is referenced from the first positive CLK edge after the last data input.





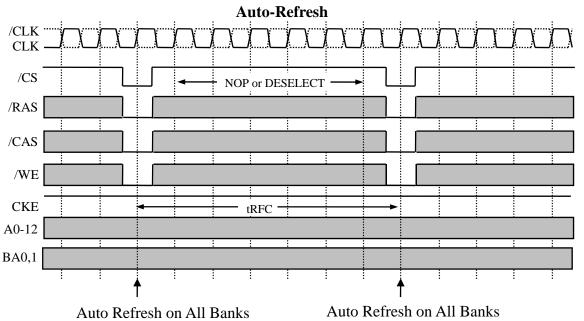


[Initialize and Mode Register sets]



[AUTO REFRESH]

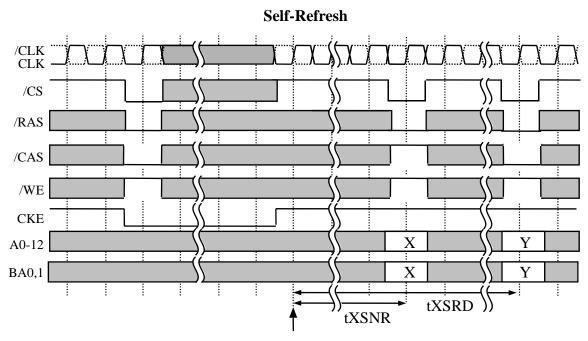
Single cycle of auto-refresh is initiated with a REFA(/CS=/RAS=/CAS=L,/WE=CKE=H) command. The refresh address is generated internally. 8192 REFA cycles within 64ms refresh 512Mbits memory cells. The auto-refresh is performed on 4 banks concurrently. Before performing an auto refresh, all banks must be in the idle state. Auto-refresh to auto-refresh interval is minimum tRFC . Any command must not be supplied to the device before tRFC from the REFA command.





[SELF REFRESH]

Self-refresh mode is entered by issuing a REFS command (/CS=/RAS=/CAS=L,/WE=H,CKE=L). Once the self-refresh is initiated, it is maintained as long as CKE is kept low. During the self-refresh mode, CKE is asynchronous and the only enable input, all other inputs including CLK are disabled and ignored, so that power consumption due to synchronous inputs is saved. To exit the self-refresh, supplying stable CLK inputs, asserting DESEL or NOP command and then asserting CKE for longer than tXSNR/tXSRD.

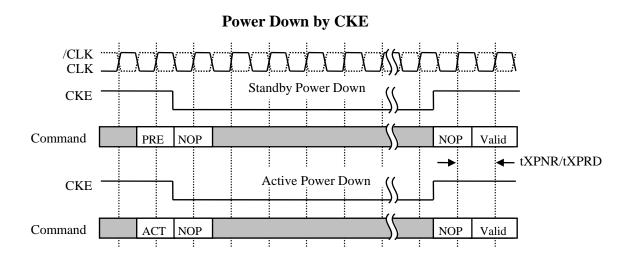


Self Refresh Exit



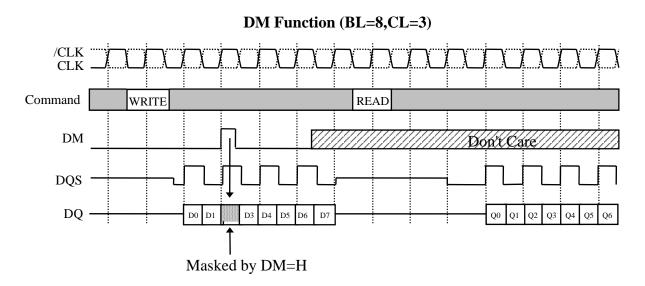
[Power DOWN]

The purpose of CLK suspend is power down. CKE is synchronous input except during the self-refresh mode. A command at cycle is ignored. From CKE=H to normal function, DLL recovery time is NOT required in the condition of the stable CLK operation during the power down mode.



[DM CONTROL]

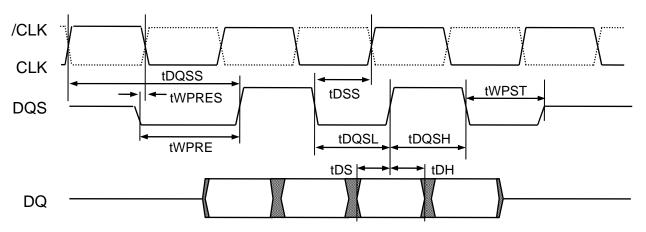
DM is defined as the data mask for writes. During writes, DM masks input data word by word. DM to write mask latency is 0.



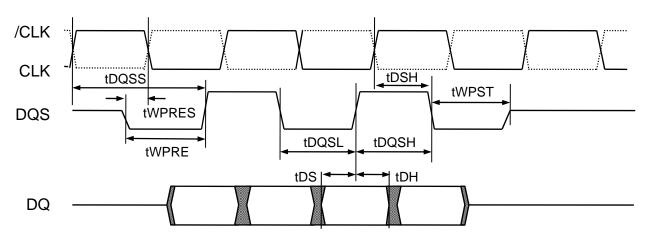


Read Operation /CLK CLK DQS tRPRE tDQSCK tQH tQH tAC

Write Operation / tDQSS=max.



Write Operation / tDQSS=min.



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Conditions	Ratings	Unit
Vdd	Supply Voltage	with respect to Vss	-1 ~ 3.6	V
VddQ	Supply Voltage for Output	with respect to VssQ	-1 ~ 3.6	V
VI	Input Voltage	with respect to Vss	-0.5 ~ Vdd+0.5	V
VO	Output Voltage	with respect to VssQ	-0.5 ~ VddQ+0.5	V
IO	Output Current		50	mA
Pd	Power Dissipation	Ta = 25 °C	1600	mW
Topr	Operating Temperature		0 ~ 70	°C
Tstg	Storage Temperature		-55 ~ 150	°C

DC OPERATING CONDITIONS

 $(Ta=0 \sim 70^{\circ}C, unless otherwise noted)$

C1 1	D		Limits		T T 14	N-4
Symbol	Parameter	Min.	Тур.	Max.	Unit	Notes
Vdd	Supply Voltage	2.5	2.6	2.7	V	-5
Vdd	Supply Voltage	2.3	2.5	2.7	V	-6
VddQ	I/O Supply Voltage	2.5	2.6	2.7	V	-5
VddQ	I/O Supply Voltage	2.3	2.5	2.7	V	-6
VREF	I/O Reference Volatage	0.49*VddQ	0.5*VddQ	0.51*VddQ	V	
VTT	I/O Termination Voltage	VREF-0.04	VREF	VREF+0.04	V	
VIH(DC)	Input High Voltage	Vref+0.15		Vdd+0.3	V	
VIL(DC)	Input Low Voltage	-0.3		Vref-0.15	V	
VIN(DC)	Input Voltage Level, CK and /CK inputs	-0.3		VddQ+0.3	V	
VID(DC)	Input Differential Voltage, CK and /CK inputs	0.3		VddQ+0.6	V	
IL	Input Leakage Current, Any input 0V <vin<vdd (all="" not="" other="" pins="" test="0V)</td" under=""><td>-2</td><td></td><td>2</td><td>uA</td><td></td></vin<vdd>	-2		2	uA	
IOZ	Output Leakage Current DQs are disabled; 0V <vout<vddq< td=""><td>-5</td><td></td><td>5</td><td>uA</td><td></td></vout<vddq<>	-5		5	uA	
IOH	Output High Current (VOUT=1.95V)	-16.8			mA	
IOL	Output Low Current (VOUT=0.35V)	16.8			mA	

CAPACITANCE

(Ta=25°C, unless otherwise noted)

Symbol	Parameter	Test Condition	Lir	nits	Delta	Unit	Notes	
Symbol	rarameter	Test Condition	Min.	Max.	Cap.(Max.)	Oilit		
CI(A)	Input Capacitance, address pin	Vcc=2.5v	2.0	3.0	0.50	pF	11	
CI(C)	Input Capacitance, control pin	f=1MHz	2.0	3.0	0.50	pF	11	
CI(K)	Input Capacitance, CLK pin		2.0	3.0	0.25	pF	11	
CI/O	I/O Capacitance, I/O, DQS, DM pin		4.0	5.0	0.50	pF	11	

512M Double Data Rate Synchronous DRAM

AVERAGE SUPPLY CURRENT from Vdd

 $(Ta=0 \sim 70^{\circ}C, Vdd = VddQ = 2.5V \pm 0.2V (-6), Vdd = VddQ = 2.6V \pm 0.1V (-5), Vss = VssQ = 0V, Output Open, unless otherwise noted)$

Symbol	Parameter/Test Conditions	Limits(Max.)		I Init	Notes
Symbol	Parameter/Test Conditions	-5	-6	Unit	Notes
IDD0	OPERATING CURRENT: One Bank; Active-Precharge; tRC = tRC MIN; tCK = tCK MIN; DQ, DM and DQS inputs changing twice per clock cycle; address and control inputs changing once per clock cycle	130	125		
IDD1	OPERATING CURRENT: One Bank; Active-Read-Precharge;Burst = 2; t RC = t RC MIN; t CK = t CK MIN; IOUT= 0mA; Address and control inputs changing once per clock cycle	135	130		
IDD2P	PRECHARGE POWER-DOWN STANDBY CURRENT: All banks idle; power-down mode; CKE ≤VIL (MAX); t CK = t CK MIN	30	25		
IDD2N	IDLE STANDBY CURRENT: $/CS \ge VIH$ (MIN); All banks idle; CKE $\ge VIH$ (MIN); t CK = t CK MIN; Address and other control inputs changing once per clock cycle	65	60		
IDD3P	ACTIVE POWER DOWN STANDBY CURRENT: One bank active; power down mode; $CKE \le VIL(MAX)$; $CK = t CK MIN$		30		
IDD3N	ACTIVE STANDBY CURRENT: /CS ≥ VIH (MIN); CKE ≥ VIH (MIN); One bank; Active-Precharge; t RC = t RAS MAX; t CK = t CK MIN; DQ,DM and DQS inputs changing twice per clock cycle; address and other control inputs changing once per clock cycle		70	mA	
IDD4R	OPERATING CURRENT: Burst =2; Read; Continuous burst;One bank active; Address and control inputs changing once per clock cycle; t CK = t CK MIN; IOUT = 0 mA		130		
	OPERATING CURRENT: Burst =2; Write; Continuous burst;One bank active; Address and control inputs changing once per clock cycle; t CK = t CK MIN; DQ and DQS inputs changing twice per clock cycle		160		
IDD5	AUTO REFRESH CURRENT: t RC = t RFC (MIN)		225		
IDD6	SELF REFRESH CURRENT: CKE ≤ 0.2V	9	9		9
IDD7	OPERATING CURRENT- Four bank Operation: Four bank interleaving with BL =4 -Refer to the Notes 20	385	335		20

AC OPERATING CONDITIONS AND CHARACTERISTICS

 $(Ta=0 \sim 70^{\circ}C, unless otherwise noted)$

Symbol	Parameter	Limits				Notes
Symbol		Min.	Тур.	Max.	Oilit	Notes
VIH(AC)	Input High Voltage	Vref+0.31			V	
VIL(AC)	Input Low Voltage			Vref-0.31	V	
VID(AC)	Input Differential Voltage, CK and /CK in	0.7		VddQ+0.6	V	
VIX(AC)	Input Crossing Point Voltage, CK and /CK input	0.5*VddQ-0.2	0.5*VddQ	0.5*VddQ+0.2	V	

AC TIMING REQUIREMENTS

 $(Ta=0 \sim 70^{\circ}C, unless otherwise noted)$

Symbol	AC Characteristics Parameter		-5		-6		Unit	Notes
Symbol			Min.	Max	Min.	Max	Ullit	110168
tAC	DQ Output access time from CLK//CLK		-0.70	+0.70	-0.70	+0.70	ns	
tDQSCK	DQS Output access time from CLK//CLK		-0.6	+0.6	-0.60	+0.60	ns	
tCH	CLK High level width		0.45	0.55	0.45	0.55	tCK	
tCL	CLK Low level width		0.45	0.55	0.45	0.55	tCK	
tCK	CLK cycle time	CL=3	5	10	6	10	ns	
iCK		CL=2.5	6	10	6	10	ns	
tDS	Input Setup time (DQ,DM)		0.4		0.45		ns	
tDH	Input Hold time(DQ,DM)		0.4		0.45		ns	
tIPW	Control & address input pulse width (for each input)		2.2		2.2		ns	
tDIPW	DQ and DM input pulse width (for each input)		1.75		1.75		ns	
tHZ	Data-out-high impedance time from CLK//CLK			+0.70		+0.70	ns	14
tLZ	Data-out-low impedance time from CLK//CLK		-0.70	+0.70	-0.70	+0.70	ns	14
tDQSQ	DQ Valid data delay time from DQS			0.40		0.45	ns	
tHP	Clock half period		tCLmin or		tCLmin or		ns	22
tQH	DQ output hold time from DQS (per access)		tCHmin tHP- tQHS		tCHmin tHP- tQHS		ns	
tQHS	Data hold skew factor (for DQS & associated DQ sign	nals)		0.50		0.55	ns	
tDQSS	Write command to first DQS latching transition		0.72	1.25	0.75	1.25	tCK	
tDQSH	DQS input High level width		0.35		0.35		tCK	
tDQSL	DQS input Low level width		0.35		0.35		tCK	
tDSS	DQS falling edge to CLK setup time		0.2		0.2		tCK	
tDSH	DQS falling edge hold time from CLK		0.2		0.2		tCK	
tMRD	Mode Register Set command cycle time		2		2		tCK	
tWPRES	Write preamble setup time		0		0		ns	16
tWPST	Write postamble		0.4	0.6	0.4	0.6	tCK	15
tWPRE	Write preamble		max(0.25* tCK, 1.5ns)		0.25*tCK		ns	
tIS	Input Setup time (address and control)		0.6		0.75		ns	19
tIH	Input Hold time (address and control)		0.6		0.75		ns	19
tRPST	Read postamble		0.4	0.6	0.4	0.6	tCK	
tRPRE	Read preamble		0.9	1.1	0.9	1.1	tCK	

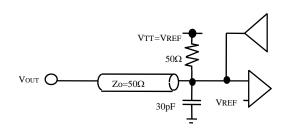


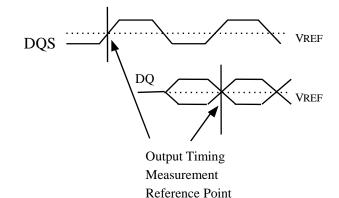
AC TIMING REQUIREMENTS(Continues)

 $(Ta=0 \sim 70^{\circ}C, unless otherwise noted)$

Cumbal	AC Characteristics Parameter	-5		-6		Unit	Notes
Symbol		Min.	Max	Min.	Max	Oilit	Notes
tRAS	Row Active time	40	70,000	42	70,000	ns	
tRC	Row Cycle time(operation)	55		60		ns	
tRFC	Auto Ref. to Active/Auto Ref. command period	70		72		ns	
tRCD	Row to Column Delay	15		18		ns	
tRAP	Active to Autoprecharge Delay	15		18		ns	
tRP	Row Precharge time	15		18		ns	
tRRD	Act to Act Delay time	10		12		ns	
tWR	Write Recovery time	15		15		ns	
tDAL	Auto Precharge write recovery + precharge time					tCK	21
tWTR	Internal Write to Read Command Delay	2		1		tCK	
tXSNR	Exit Self Ref. to non-Read command	75		75		ns	
tXSRD	Exit Self Ref. to -Read command	200		200		tCK	
tXPNR	Exit Power down to command	1		1		tCK	
tXPRD	Exit Power down to -Read command	1		1		tCK	18
tREFI	Average Periodic Refresh interval		7.8		7.8	μs	17

Output Load Condition







512M Double Data Rate Synchronous DRAM

Notes

- 1. All voltages referenced to Vss.
- Tests for AC timing, IDD, and electrical, AC and DC characteristics, may be conducted at nominal reference/supply voltage levels, but the related specifications and device operation are guaranteed for the full voltage range specified.
- 3. AC timing and IDD tests may use a VIL to VIH swing of up to 1.5V in the test environment, but input timing is still referenced to VREF (or to the crossing point for CK//CK), and parameter specifications are guaranteed for the specified AC input levels under normal use conditions. The minimum slew rate for the input signals is 1V/ns in the range between VIL(AC) and VIH(AC).
- 4. The AC and DC input level specifications are as defined in the SSTL_2 Standard (i.e. the receiver will effectively switch as a result of the signal crossing the AC input level, and will remain in that state as long as the signal does not ring back above (below) the DC input LOW (HIGH) level.
- 5. VREF is expected to be equal to 0.5*VddQ of the transmitting device, and to track variations in the DC level of the same. Peak-to-peak noise on VREF may not exceed +2% of the DC value.
- VTT is not applied directly to the device. VTT is a system supply for signal termination resistors, is expected to be set equal to VREF, and must track variations in the DC level of VREF.
- 7. VID is the magnitude of the difference between the input level on CLK and the input level on /CLK.
- 8. The value of VIX is expected to equal 0.5*VddQ of the transmitting device and must track variations in the DC level of the same.
- 9. Enables on-chip refresh and address counters.
- 10. IDD specifications are tested after the device is properly initialized.
- 11. This parameter is sampled. VddQ = 2.5V±0.2V, Vdd = 2.5V±0.2V, f = 100 MHz, Ta = 25°C, VOUT(DC) = VddQ/2, VOUT(PEAK TO PEAK) = 25mV. DM inputs are grouped with I/O pins reflecting the fact that they are matched in loading (to facilitate trace matching at the board level).
- 12. The CLK//CLK input reference level (for timing referenced to CLK//CLK) is the point at which CLK and /CLK cross; the input reference level for signals other than CLK//CLK, is VREF.
- 13. Inputs are not recognized as valid until VREF stabilizes. Exception: during the period before VREF stabilizes, CKE< 0.3VddQ is recognized as LOW.
- 14. tHZ and tLZ transitions occur in the same access time windows as valid data transitions. These parameters are not referenced to a specific voltage level, but specify when the device output is no longer driving (HZ), or begins driving (LZ).
- 15. The maximum limit for this parameter is not a device limit. The device will operate with a greater value for this parameter, but system performance (bus turnaround) will degrade accordingly.
- 16. The specific requirement is that DQS be valid (HIGH, LOW, or at some point on a valid transition) on or before this CLK edge. A valid transition is defined as monotonic, and meeting the input slew rate specifications of the device. When no writes were previously in progress on the bus, DQS will be transitioning from High-Z to logic LOW. If a previous write was in progress, DQS could be HIGH, LOW, or transitioning from HIGH to LOW at this time, depending on tDQSS.
- 17. A maximum of eight AUTO REFRESH commands can be posted to any given DDR SDRAM device.
- 18. tXPRD should be 200 tCLK in the condition of the unstable CLK operation during the power down mode.
- 19. For command/address and CK & /CK slew rate > 1.0V/ns.
- 20. IDD7: Operating current:Four Bank

For Bank are being interleaved with tRC(min),Burst Mode,Address and Control inputs on NOP edge are not changing. Iout = 0mA

Timing patterns:

tCK=min,tRRD=2*tCK,BL=4,tRCD=3*tCK,Read with Autoprecharge

Read: A0 N A1 R0 A2 R1 N R3 A0 N A1 R0 – repeat the same timing with random address changing

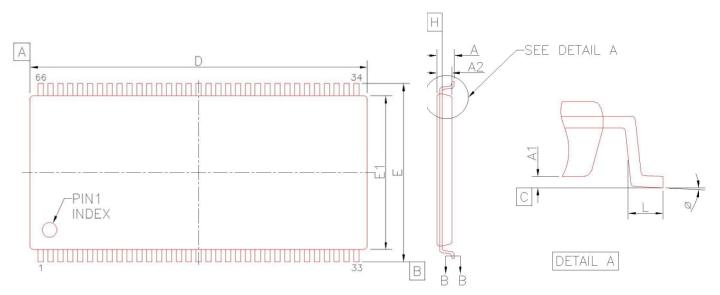
*100% of data changing at every burst

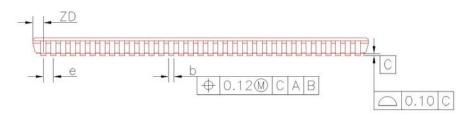
Legend: A=Activate, R=Read, P=Precharge, N=NOP

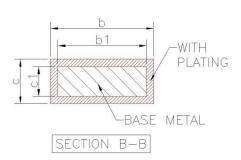
- 21. tDALminimum = (tWR/tCK) + (tRP/tCK).
 - For each of the terms above, if not already an integer, round to the next highest integer.
- 22. Min (tCL,tCH) refers to the smaller of the actual clock low time and the actual clock high time as provided to the device.



PACKAGE DRAWING







Symbol	MILLIMETERS					
Symbol	MIN.	NOM.	MAX.			
Α			1.20			
Α1	0.05		0.15			
A2	0.95	1.00	1.05			
b	0.22		0.38			
b1	0.22		0.33			
C	0.12		0.21			
c1	0.12	0.127	0.16			
D	22.12	22.22	22.32			
Е	11.56	11.76	11.96			
E1	10.06	10.16	10.26			
L	0.40	0.50	0.60			
е	0.65 BSC					
Ø	0,		8°			
ZD	0.71 REF					



A4S12D30FTP A4S12D40FTP 512M Double Data Rate Synchronous DRAM

Important Notice:

Zentel DRAM products are not intended for medical implementation, airplane and transportation instrument, safety equipments, or any other applications for life support or where Zentel products failure could result in life loss, personal injury, or environment damage. Zentel customers who purchase Zentel products for use in such applications do so in their own risk and fully agree Zentel accepts no liability for any damage from this improper use.